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Application/Control No.	Applicant(s)/Patent under Reexamination
10/766,466	CHIOLA ET AL.
Examiner	Art Unit
Thien F. Tran	2811

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SEARCHED			
Class	Subclass	Date	Examiner
257	471-473	4/20/2005	тт
257	481-486	4/20/2005	тт
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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(INCLUDING	ARCH NOTES SEARCH STRATEGY	<u>') </u>
	DATE	EXMR
EASt ·	4/20/2005	тт
EAST	4/21/2005	тт